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MT-203

Ciência e Tecnologia de Filmes Finos

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Aula de Exercícios

- Cap 2: 1, 3, 5, 6, 9
- Cap 3: 3, 4, 5, 9,
- Cap 4: 7, 8, 11, 13
- Cap 5: 1, 2, 3, 4, 6, 7, 8, 13
- Cap 6: 1, 3, 14

Cap 2

2.5

2.5 An Al film is being deposited at 5 $\mu\text{m/h}$ in a background of 1×10^{-7} torr of O_2 . What will be the maximum atomic percent oxygen in the deposit?

$$J_r \left(\frac{\text{mc}}{\text{cm}^2 \cdot \text{s}} \right) = 1.67 \times 10^{16} \frac{\frac{dh}{dt} (\mu\text{m/h}) \rho_m (\text{g/cm}^3)}{M (\text{g/mol})}$$

$$J_i \left(\frac{\text{mc}}{\text{m}^2 \cdot \text{s}} \right) = \frac{N_A p}{\sqrt{2\pi M R T}}$$

Cap 2

2.9 Single-crystal Si is being deposited at $1.0 \mu\text{m/h}$ onto one face of a 4 inch diameter heated substrate in a CVD process by pyrolysis (thermal decomposition) of the reactant dichlorosilane (SiH_2Cl_2) flowing at 10 sccm. What fraction of the reactant is being utilized in the deposition?

$$J_r \left(\frac{\text{mc}}{\text{cm}^2 \cdot \text{s}} \right) = 1.67 \times 10^{16} \frac{\frac{dh}{dt} (\mu\text{m/h}) \rho_m (\text{g/cm}^3)}{M (\text{g/mol})}$$

2.3 Show that $1 \text{ sccm} = 4.48 \times 10^{17} \text{ mc/s}$.

Cap 3

3.4 A process chamber of 1 m^2 surface area is outgassing at a rate of $10^{13} \text{ mc/cm}^2 \cdot \text{s}$. For a process-gas flow of 200 sccm and a total pressure of 100 Pa, what is the partial pressure of the outgassing impurities?

$$J_i \left(\frac{\text{mc}}{\text{m}^2 \cdot \text{s}} \right) = \frac{N_A P}{\sqrt{2\pi MRT}}$$

2.3 Show that $1 \text{ sccm} = 4.48 \times 10^{17} \text{ mc/s}$.

Cap 3

3.9 How many seconds will it take for a 1 cm^3 virtual leak to evacuate from 10^2 to 10^{-6} Pa through a 10^{-2} cm -diameter, 1 cm-long capillary?

$$\text{Kn} = l/L$$

$$C_m = 12.3\phi^3/L \quad \text{l/s}$$

$$C_f = 1.41\phi^4 \bar{p}/L \quad \text{l/s}$$

- L = menor dimensão interna do sistema (largura, distância entre eletrodos, etc...)
- $\text{Kn} > 1$ → sistema está em **regime molecular**
- $\text{Kn} < 0,01$ → sistema está em **regime fluido** (viscoso)
- $0,01 \leq \text{Kn} \leq 1$ → sistema está em **regime de transição** (intermediário)

ϕ = tube diameter, cm
 L = tube length, cm; $L \gg \phi$

Cap 3

3.9 How many seconds will it take for a 1 cm^3 virtual leak to evacuate from 10^2 to 10^{-6} Pa through a 10^{-2} cm -diameter, 1 cm-long capillary?

$$\left. \begin{aligned} Q &= C \Delta p \\ -\frac{dN}{dt} &= C p \quad (p_o = 0) \\ -\frac{V}{RT} \frac{dp}{dt} &= \frac{12,3 \Phi^3}{L} p \end{aligned} \right\} = \Delta t$$

$$\Delta t = \frac{V}{RT} \frac{L}{12,3 \Phi^3} \int_{p_f}^{p_i} \frac{dp}{p}$$

$$\Delta t = \frac{V}{RT} \frac{L}{12,3 \Phi^3} \ln \left[\frac{p_i}{p_f} \right]$$

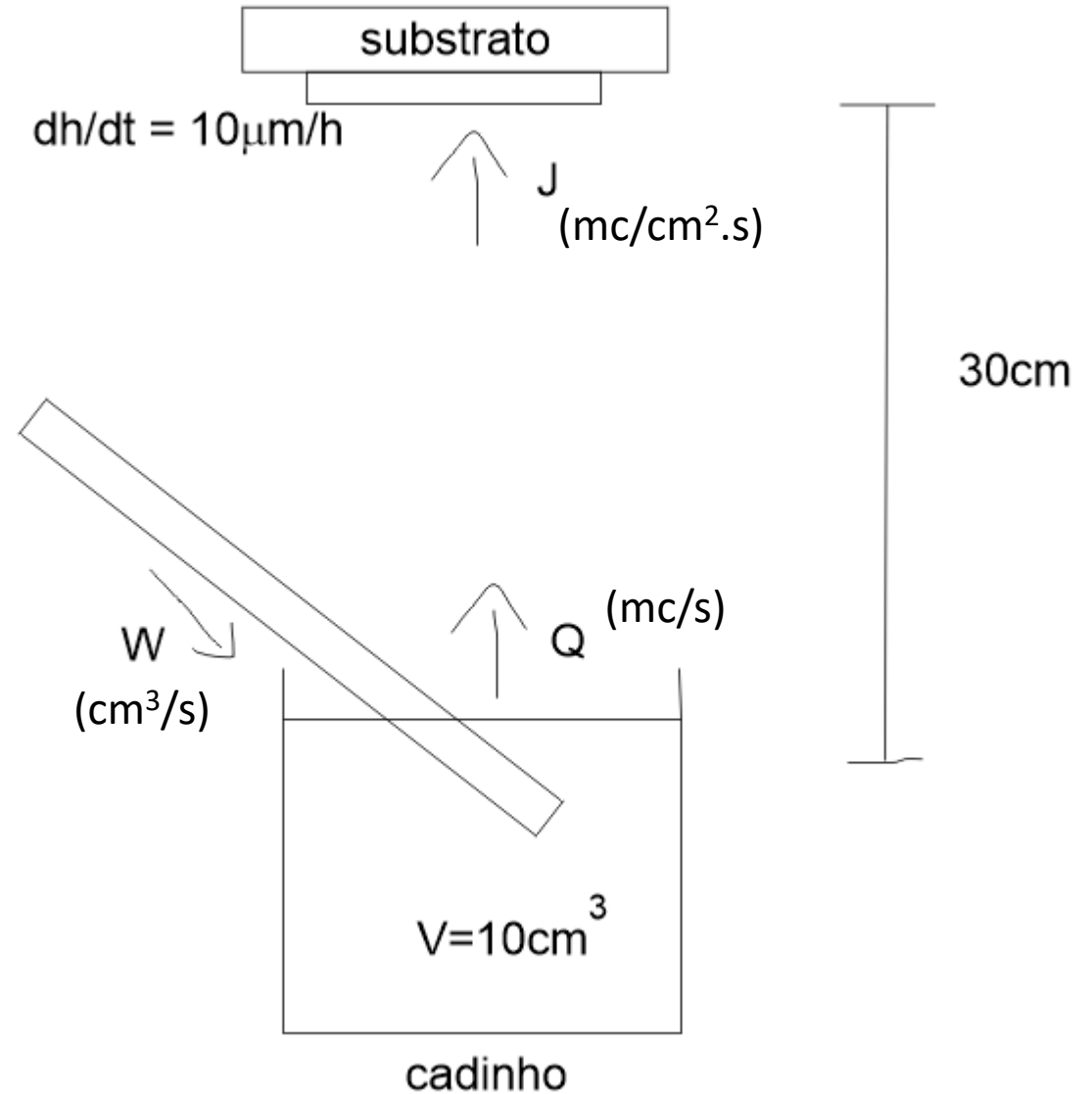
Cap 4

4.7 An alloy is being deposited by wire feed into a crucible melt having $V = 10 \text{ cm}^3$. The deposition rate on a substrate 30 cm directly above the crucible is $10 \text{ }\mu\text{m/h}$. (a) Assuming cosine-law effusion, what is the volume feed rate of wire, W , required to hold V constant after the melt reaches steady-state composition? (b) How many hours will it take for the melt to drift 90 percent of the way from initial to steady-state composition, assuming that $\tau = V/W$?

Cap 4

4.7 (a)

$$J_r \left(\frac{\text{mc}}{\text{cm}^2 \cdot \text{s}} \right) = 1.67 \times 10^{16} \frac{\frac{dh}{dt} (\mu\text{m/h}) \rho_m (\text{g/cm}^3)}{M (\text{g/mol})}$$



4.7 (a)

[illegible]

Cap 4

4.7 (b) $t = ?$, para $\xi = 0.9$

$$\xi = \frac{\mathbf{x}_s - \mathbf{x}}{\mathbf{x}_s - \mathbf{y}} = \exp\left(\frac{-t}{V\mathbf{x}_s/W\mathbf{y}}\right) = e^{-t/\tau} \quad (4.25)$$

Cap 4

4.7 (b) $t = ?$, para $\xi = 0.9$

$$\xi = \exp\left(\frac{-t}{\tau_w}\right) \quad (4.25)$$

Cap 4

4.11

4.11 Show by integration that, for a cosine distribution of evaporant, the evaporant flux perpendicular to the source plane is twice the average flux over the hemisphere.

$$J_s = J_\theta \cos^2 \theta$$

$$\frac{1}{2\pi} \int_0^{2\pi} \cos^2 \theta \, d\theta$$

Exercícios (aula 4)

1) Sabendo que um filme de 500nm de silício cristalino é crescido em 2 horas. Qual o tempo médio para formação de 1 camada atômica (monocamada) de Si no filme em crescimento? Suponha crescimento bidimensional no plano (111).

Dados:

$$\rho = 2.330 \text{ kg/m}^3 = 2,33 \text{ g/cm}^3$$

$$M = 28,1 \text{ uma} = 28,1 \text{ g/mol}$$

$$a \text{ (parâmetro de rede)} = 0,357 \text{ nm}$$

Difusão Superficial

Mas enquanto o precursor passeia na superfície, o filme está crescendo:

➤ Para um filme de 500 nm de Si (100) – estrutura diamante - crescido em 2 horas:

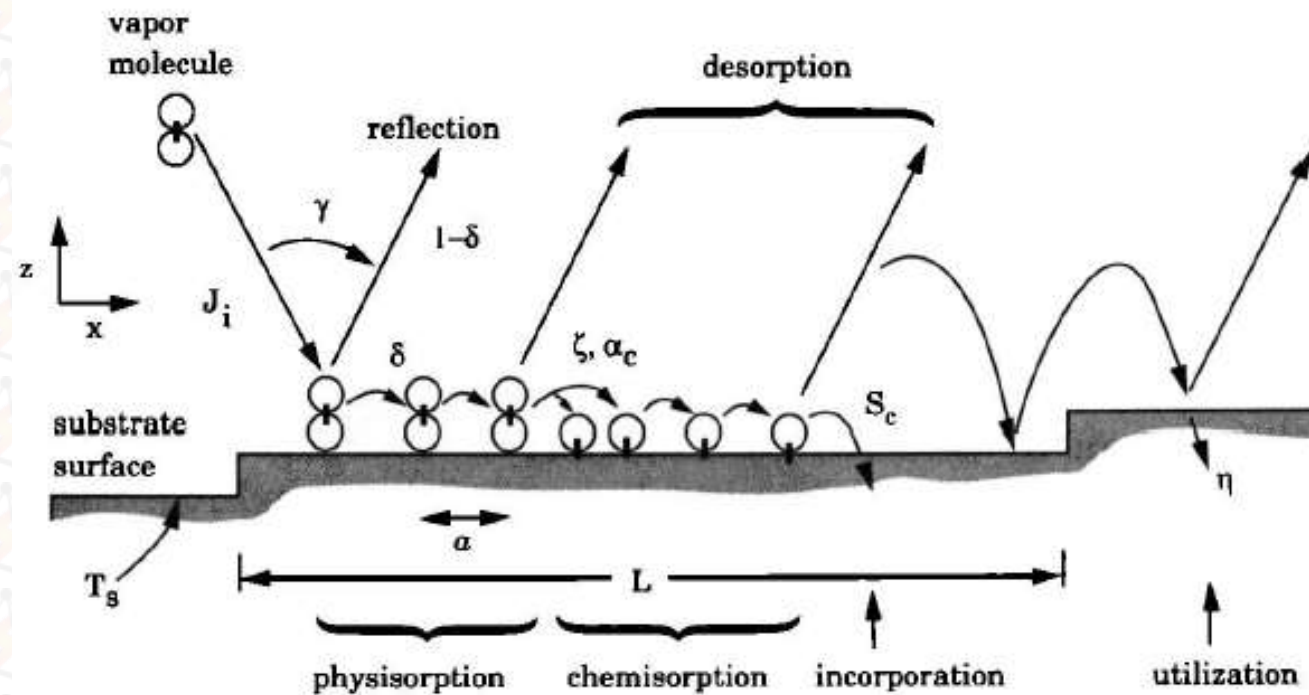
- $dh/dt = 0,25 \mu\text{m}/h = 250\text{nm}/3600\text{s} = 0,0694 \text{ nm/s}$
- Parâmetro de rede do Si = 0,357 nm
- São 4 camadas atômicas (100) por cela
- Espessura da camada atômica = $0,357/4 = 0,089 \text{ nm}$
- t (monocamada (100)) = 1,95 s

▪ Outra forma de calcular:

$$J_r \left(\frac{\text{mc}}{\text{cm}^2 \cdot \text{s}} \right) = 1.67 \times 10^{16} \frac{\frac{dh}{dt} (\mu\text{m}/h) \rho_m (\text{g}/\text{cm}^3)}{M (\text{g}/\text{mol})}$$

Cap 5

5.1 A molecule has a condensation coefficient of $\alpha_c = 0.2$ on a depositing film of its own solid phase. For this molecule, what are the minimum and maximum values of the thermal accommodation coefficient, γ ; trapping probability, δ ; sticking coefficient, S_c ; and utilization factor, η ?



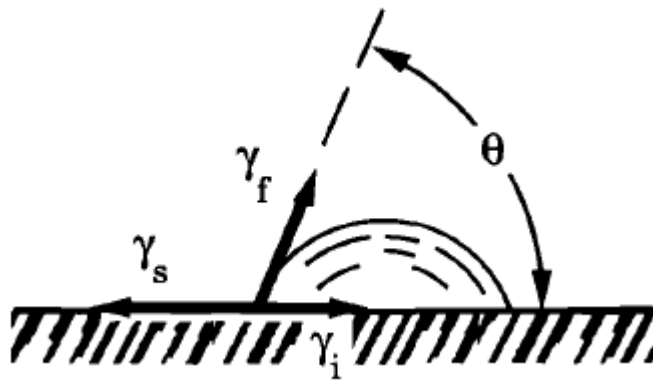
Cap 5

- 5.3 For condensation onto nonwetting substrates at 300 K using a 10^{-4} Pa overpressure, what are the classical critical-nucleus radii for the following metals, neglecting substrate contact area and γ_f anisotropy? (a) Au, with $\gamma_f = 1400$ ergs/cm² (dynes/cm); (b) Pb, with $\gamma_f = 560$ ergs/cm².

$$r^* = \frac{2\gamma_f}{\left(\frac{RT}{V_{mc}}\right) \ln\left(\frac{p}{p_v}\right)}$$

Cap 5

5.4 Derive Young's equation [Eq. (5.45)] using surface-energy minimization.

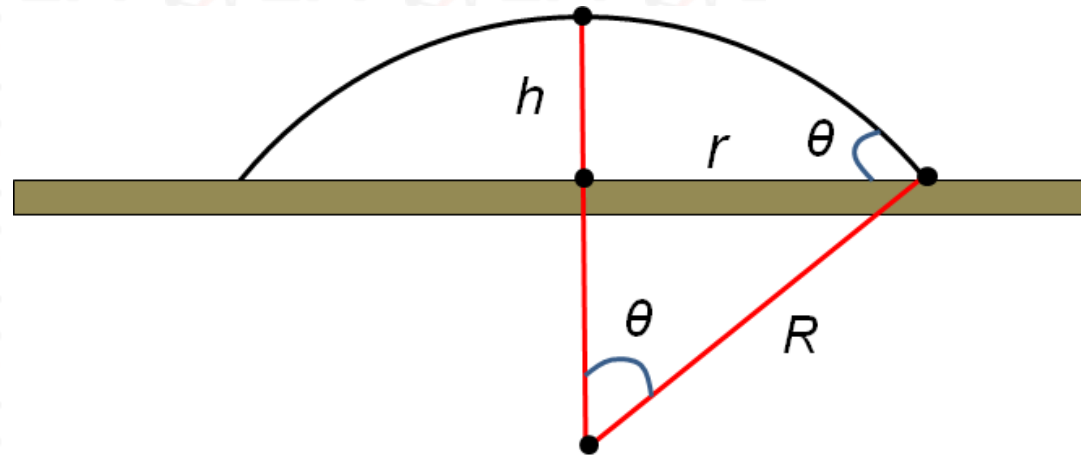


$$\gamma_i + \gamma_f \cos \theta = \gamma_s$$

Cap 5

5.4

$V = \text{constante}$



$$A = 2\pi Rh \text{ or } A = 2\pi R^2(1 - \cos\theta).$$

$$V = \frac{\pi h}{6}(3r^2 + h^2) \quad V = \frac{\pi R^3}{3}(1 - \cos\theta)^2(2 + \cos\theta) \quad \frac{d\theta}{dR} = -\frac{(1 - \cos\theta)(2 + \cos\theta)}{R \sin\theta(1 + \cos\theta)}$$

$$E = \pi r^2(\gamma_i - \gamma_s) + 2\pi Rh \cdot \gamma_f = \pi(R \sin\theta)^2(\gamma_i - \gamma_s) + 2\pi R^2(1 - \cos\theta)\gamma_f$$

$dE/dR = 0$ (minimização da energia)

Cap 6

- 6.1 For epitaxy of CdTe(111) on GaAs(001) as shown in Fig. 6.1c: (a) show by a geometrical construction similar to Fig. 5.7 that the $[2\bar{1}1]$ direction of CdTe does indeed lie in the (111) plane. (b) Using the a_0 data of Fig. 6.3, calculate the atomic spacing a shown in Fig. 6.1c for GaAs and for CdTe.

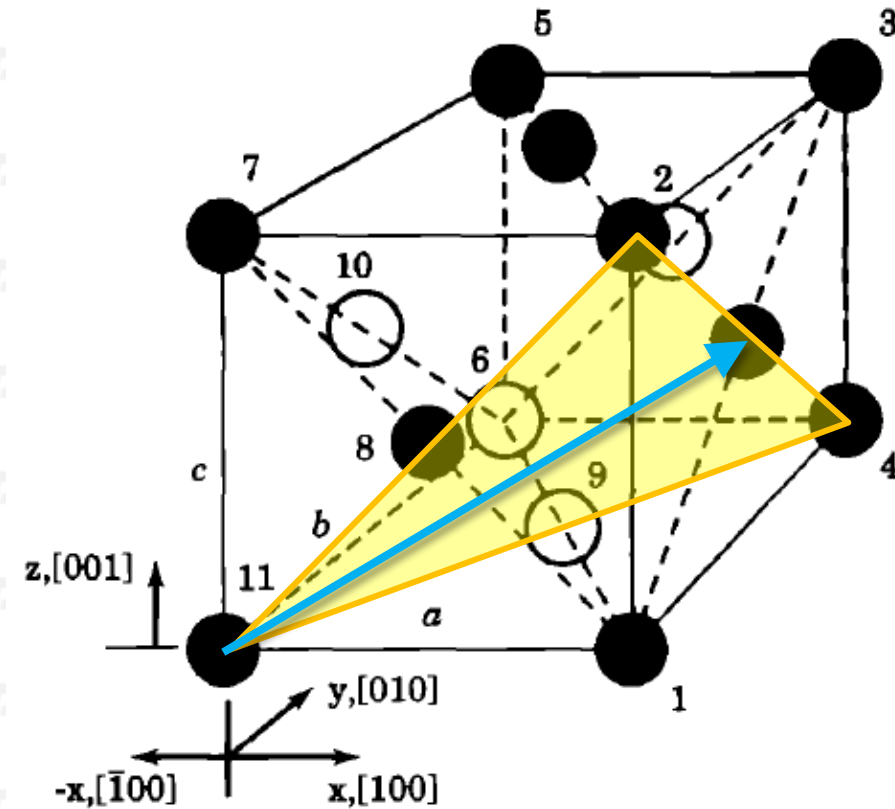
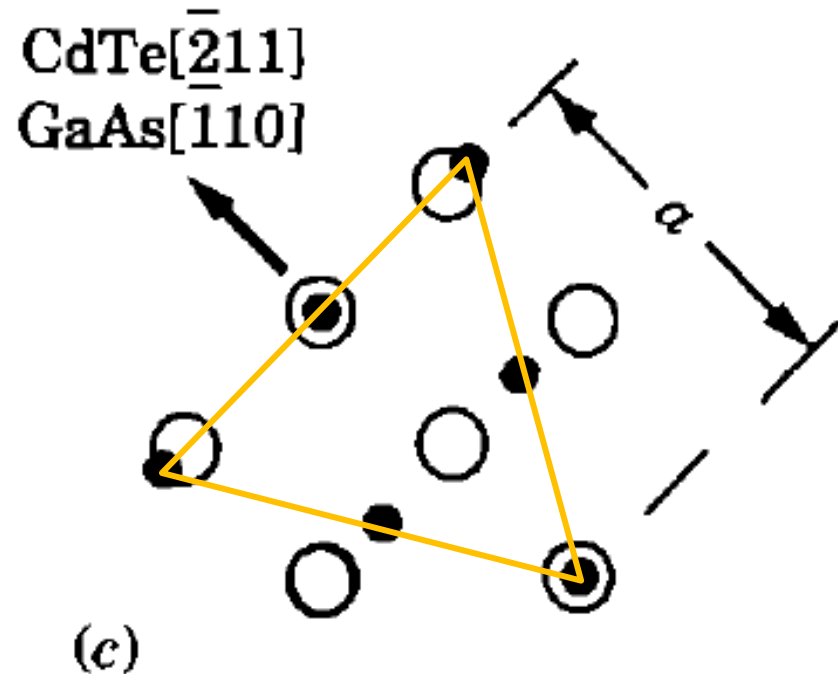


Figure 5.7 Geometry of a face-centered cubic crystal.

Cap 6

- 6.1 For epitaxy of CdTe(111) on GaAs(001) as shown in Fig. 6.1c: (a) show by a geometrical construction similar to Fig. 5.7 that the $[2\bar{1}1]$ direction of CdTe does indeed lie in the (111) plane. (b) Using the a_0 data of Fig. 6.3, calculate the atomic spacing a shown in Fig. 6.1c for GaAs and for CdTe.

